



## Subject card

|   |  |   |                                     |            |   |         |     |
|---|--|---|-------------------------------------|------------|---|---------|-----|
| Subject name and code                       | Diffraction methods of structural analysis, PG_00058968  |   |                                     |            |   |         |     |
| Field of study                              | Nanotechnology   |   |                                     |            |   |         |     |
| Date of commencement of studies             | October 2022   | Academic year of realisation of subject   |                                     |            | 2024/2025   |         |     |
| Education level                             | first-cycle studies  | Subject group   |                                     |            |   |         |     |
| Mode of study                               | Full-time studies  | Mode of delivery  |                                     |            | at the university                                       |         |     |
| Year of study                               | 3  | Language of instruction   |                                     |            | Polish  |         |     |
| Semester of study                           | 5  | ECTS credits  |                                     |            | 4.0   |         |     |
| Learning profile                            | general academic profile   | Assessment form   |                                     |            | assessment  |         |     |
| Conducting unit                             | Department of Solid State Physics -> Faculty of Applied Physics and Mathematics  |   |                                     |            |   |         |     |
| Name and surname of lecturer (lecturers)    | Subject supervisor   | prof. dr hab. inż. Tomasz Klimczuk  |                                     |            |   |         |     |
|   | Teachers   | prof. dr hab. inż. Tomasz Klimczuk  |                                     |            |   |         |     |
| Lesson types and methods of instruction     | Lesson type  | Lecture   | Tutorial                            | Laboratory | Project   | Seminar | SUM |
|   | Number of study hours  | 15.0  | 0.0                                 | 30.0       | 0.0   | 0.0     | 45  |
|   | E-learning hours included: 0.0   |   |                                     |            |   |         |     |
| Learning activity and number of study hours | Learning activity  | Participation in didactic classes included in study plan  | Participation in consultation hours | Self-study | SUM   |         |     |
|   | Number of study hours  | 45  | 0.0                                 | 0.0        | 45  |         |     |
| Subject objectives                          | The aim of the course is to train students with the various diffraction methods and computer tools for analysis xrd data and visualization of crystal structures.  |   |                                     |            |   |         |     |
| Learning outcomes                           | Course outcome   | Subject outcome   |                                     |            | Method of verification                                  |         |     |
|   | K6_K05   | The student critically evaluates his own performance, constructively evaluates the results of the work of others.   |                                     |            | [SK2] Assessment of progress of work                    |         |     |
|   | K6_W07   | The student is an expert in the physical and chemical basis of nanotechnology.  |                                     |            | [SW2] Assessment of knowledge contained in presentation |         |     |
|   | K6_U06   | The student accurately, clearly but not oversimplified, explains even the most intricate technological and scientific problems related to the manufacture and applications of nanostructures. |                                     |            | [SU2] Assessment of ability to analyse information      |         |     |
| Subject contents                            | 1. Introduction to the course. (2 hours)2. Diffraction methods. (4 hours)3. Introduction to Database ICSD / FindIt and CoD. Simulations using PowderCell. (2 hours)4. Visualization of crystal structures using VESTA. (4 hours)5. Introduction to the Rietveld method and LeBail. (2 hours)6. Mathematical basis of the Rietveld method. (2 hours)7. Package FullProf Suite. (6 hours)8. Neutron diffraction methods. (4 hours)9. Practical aspects of measurements of neutron and synchrotron (infrastructure, applying for beamtime, sample preparation, etc.). (2 hours)10. The future of diffraction methods. (2 hours) |   |                                     |            |   |         |     |
| Prerequisites and co-requisites             | Basic knowledge in crystallography.  |   |                                     |            |   |         |     |
| Assessment methods and criteria             | Subject passing criteria   | Passing threshold   |                                     |            | Percentage of the final grade                           |         |     |
|   | Final test   | 60.0%   |                                     |            | 60.0%   |         |     |
|   | Practical test   | 60.0%   |                                     |            | 40.0%   |         |     |

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| Recommended reading  | Basic literature   | <ol style="list-style-type: none"> <li>1. FullProf manual: <a href="https://www.psi.ch/sinq/dmc/ManualsEN/fullprof.pdf">https://www.psi.ch/sinq/dmc/ManualsEN/fullprof.pdf</a></li> <li>2. L.B. McCusker, et al. <i>Rietveld refinement guidelines</i>, J. Appl. Cryst. (1999) vol. 32, 36-50</li> <li>3. B. H. Toby, <i>R-factors: how good is good enough?</i>, Powder Diffraction (2006) vol. 21, 67-70</li> <li>4. D. S. Sivia, <i>Elementary Scattering Theory For X-ray and Neutron Users</i>, Oxford University Press (2014)</li> <li>5. H. M. Rietveld, A profile refinement method for nuclear and magnetic structures, Journal of Applied Crystallography (1969) vol. 2, 65-71 <a href="http://epswww.unm.edu/media/pdf/Rietveld-1969-ProfileRefinement.pdf">http://epswww.unm.edu/media/pdf/Rietveld-1969-ProfileRefinement.pdf</a></li> </ol> |
|  | Supplementary literature   | <ol style="list-style-type: none"> <li>1. G. Will, <i>Powder Diffraction: The Rietveld Method and the Two Stage Method to Determine and Refine Crystal Structures from Powder Diffraction Data</i>, Springer (2006) <a href="http://link.springer.com/book/10.1007/3-540-27986-5">http://link.springer.com/book/10.1007/3-540-27986-5</a></li> </ol>  |
|  | eResources addresses   | Adresy na platformie eNauczanie:  |
| Example issues/<br>example questions/<br>tasks being completed | Using Vesta software draw and then discuss the details of the structure of Mg <sub>10</sub> Ir <sub>19</sub> B <sub>16</sub> compound. |   |
| Work placement   | Not applicable   |   |